12 V, 8.0 A, Low V_{CE(sat)} **PNP Transistor**

ON Semiconductor's e²PowerEdge family of low V_{CE(sat)} transistors are miniature surface mount devices featuring ultra low saturation voltage (V_{CE(sat)}) and high current gain capability. These are designed for use in low voltage, high speed switching applications where affordable efficient energy control is important.

Typical applications are DC–DC converters and power management in portable and battery powered products such as cellular and cordless phones, PDAs, computers, printers, digital cameras and MP3 players. Other applications are low voltage motor controls in mass storage products such as disc drives and tape drives. In the automotive industry they can be used in air bag deployment and in the instrument cluster. The high current gain allows e²PowerEdge devices to be driven directly from PMU's control outputs, and the Linear Gain (Beta) makes them ideal components in analog amplifiers.

• This is a Pb-Free Device

MAXIMUM RATINGS $(T_A = 25^{\circ}C)$

Rating	Symbol	Max	Unit
Collector-Emitter Voltage	V _{CEO}	-12	Vdc
Collector-Base Voltage	V_{CBO}	-12	Vdc
Emitter-Base Voltage	V _{EBO}	-7.0	Vdc
Collector Current - Continuous	I _C	-5.0	Adc
Collector Current – Peak	I _{CM}	-8.0	Α
Electrostatic Discharge	ESD	HBM Class 3B MM Class C	

THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit	
Total Device Dissipation, T _A = 25°C Derate above 25°C	P _D (Note 1)	875 7.0	mW mW/°C	
Thermal Resistance, Junction-to-Ambient	R _{θJA} (Note 1)	143	°C/W	
Total Device Dissipation, T _A = 25°C Derate above 25°C	P _D (Note 2)	1.5 11.8	W mW/°C	
Thermal Resistance, Junction-to-Ambient	R _{θJA} (Note 2)	85	°C/W	
Thermal Resistance, Junction–to–Lead #3	R _{θJL} (Note 2)	23	°C/W	
Total Device Dissipation (Single Pulse < 10 sec)	P _{Dsingle} (Notes 2 & 3)	3.0	W	
Junction and Storage Temperature Range	T _J , T _{stg}	-55 to +150	°C	

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

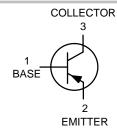
- FR-4 @ 100 mm², 1 oz copper traces.
 FR-4 @ 500 mm², 1 oz copper traces.
- 3. Thermal response.



ON Semiconductor®

http://onsemi.com

12 VOLTS **8.0 AMPS** PNP LOW V_{CE(sat)} TRANSISTOR EQUIVALENT $R_{DS(on)}$ 55 m Ω





WDFN3 **CASE 506AU**

MARKING DIAGRAM



= Specific Device Code

= Date Code

= Pb-Free Package

ORDERING INFORMATION

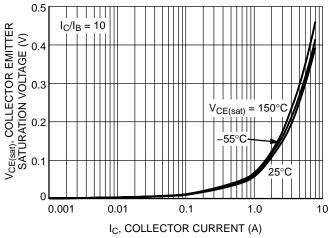
Device	Package	Shipping [†]	
NSS12500UW3T2G	WDFN3 (Pb-Free)	3000/ Tape & Reel	

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

ELECTRICAL CHARACTERISTICS ($T_A = 25^{\circ}C$ unless otherwise noted)

Characteristic	Symbol	Min	Typical	Max	Unit
OFF CHARACTERISTICS	I I		_1	ı	
Collector – Emitter Breakdown Voltage $(I_C = -10 \text{ mAdc}, I_B = 0)$	V _{(BR)CEO}	-12	_	_	Vdc
Collector – Base Breakdown Voltage $(I_C = -0.1 \text{ mAdc}, I_E = 0)$	V _{(BR)CBO}	-12	_	_	Vdc
Emitter – Base Breakdown Voltage $(I_E = -0.1 \text{ mAdc}, I_C = 0)$	V _{(BR)EBO}	-7.0	_	_	Vdc
Collector Cutoff Current (V _{CB} = 12 Vdc, I _E = 0)	Ісво	_	-	-0.1	μAdc
Emitter Cutoff Current (V _{EB} = -7.0 Vdc)	I _{EBO}	-	_	-0.1	μAdc
ON CHARACTERISTICS					
DC Current Gain (Note 4) $ \begin{aligned} &(I_C = -10 \text{ mA}, \ V_{CE} = -2.0 \text{ V}) \\ &(I_C = -500 \text{ mA}, \ V_{CE} = -2.0 \text{ V}) \\ &(I_C = -500 \text{ mA}, \ V_{CE} = -2.0 \text{ V}) \\ &(I_C = -1.0 \text{ A}, \ V_{CE} = -2.0 \text{ V}) \\ &(I_C = -2.0 \text{ A}, \ V_{CE} = -2.0 \text{ V}) \\ &(I_C = -3.0 \text{ A}, \ V_{CE} = -2.0 \text{ V}) \end{aligned} $	h _{FE}	250 250 250 250 200 180	- 300 300 250	- - - -	
Collector – Emitter Saturation Voltage (Note 4) ($I_C = -0.1 \text{ A}$, $I_B = -0.010 \text{ A}$) (Note 5) ($I_C = -1.0 \text{ A}$, $I_B = -0.100 \text{ A}$) ($I_C = -1.0 \text{ A}$, $I_B = -0.010 \text{ A}$) ($I_C = -1.0 \text{ A}$, $I_B = -0.020 \text{ A}$) ($I_C = -2.0 \text{ A}$, $I_B = -0.030 \text{ A}$) ($I_C = -3.0 \text{ A}$, $I_B = -0.030 \text{ A}$) ($I_C = -4.0 \text{ A}$, $I_B = -0.400 \text{ A}$)	V _{CE} (sat)	- - - - -	-0.008 -0.055 -0.080 -0.135 -0.190 -0.200	-0.012 -0.070 -0.100 -0.170 -0.240 -0.260	V
Base – Emitter Saturation Voltage (Note 4) $(I_C = -1.0 \text{ A}, I_B = -0.01 \text{ A})$	V _{BE(sat)}	-	0.760	-0.900	V
Base – Emitter Turn–on Voltage (Note 4) $(I_C = -2.0 \text{ A}, V_{CE} = -3.0 \text{ V})$	V _{BE(on)}	-	0.800	-0.900	V
Cutoff Frequency ($I_C = -100 \text{ mA}$, $V_{CE} = -5.0 \text{ V}$, $f = 100 \text{ MHz}$)	f _T	100	_	_	MHz
Input Capacitance (V _{EB} = -0.5 V, f = 1.0 MHz)	Cibo	-		650	pF
Output Capacitance ($V_{CB} = -3.0 \text{ V}, f = 1.0 \text{ MHz}$)	Cobo	-		210	pF
SWITCHING CHARACTERISTICS					
Delay ($V_{CC} = -10 \text{ V}, I_C = 750 \text{ mA}, I_{B1} = 15 \text{ mA}$)	t _d	_	_	100	ns
Rise ($V_{CC} = -10 \text{ V}, I_C = 750 \text{ mA}, I_{B1} = 15 \text{ mA}$)	t _r	_	_	150	ns
Storage ($V_{CC} = -10 \text{ V}, I_{C} = 750 \text{ mA}, I_{B1} = 15 \text{ mA}$)	t _s	_	_	350	ns
Fall ($V_{CC} = -10 \text{ V}, I_C = 750 \text{ mA}, I_{B1} = 15 \text{ mA}$)	t _f	-	-	200	ns

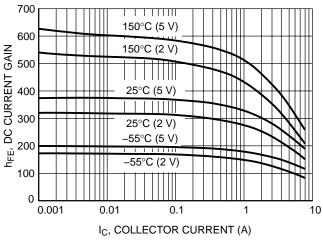
^{4.} Pulsed Condition: Pulse Width = 300 μ sec, Duty Cycle \leq 2%. 5. Guaranteed by design but not tested.



 $I_{\rm C}/I_{\rm B} = 100$ $I_{\rm C}/I_{\rm B} = 100$ $I_{\rm C}/I_{\rm B} = 100$ $I_{\rm C}/I_{\rm C}/I_{\rm B} = 100$ $I_{\rm C}/I_{\rm C}/I_{\rm$

Figure 1. Collector Emitter Saturation Voltage vs. Collector Current

Figure 2. Collector Emitter Saturation Voltage vs. Collector Current



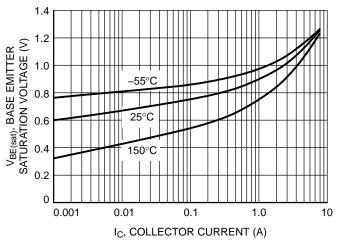
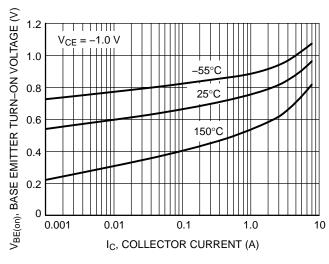


Figure 3. DC Current Gain vs. Collector Current

Figure 4. Base Emitter Saturation Voltage vs.
Collector Current



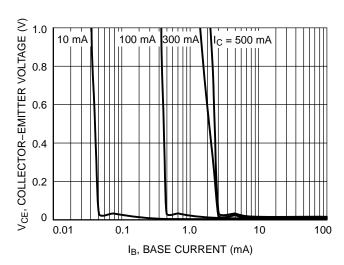


Figure 5. Base Emitter Turn-On Voltage vs. Collector Current

Figure 6. Saturation Region

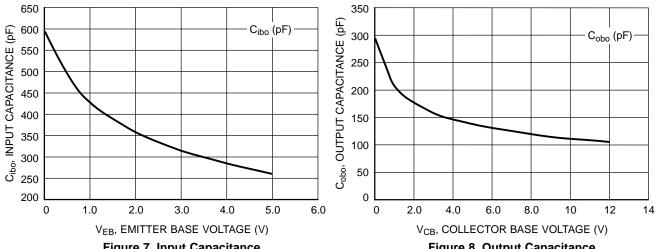


Figure 7. Input Capacitance

Figure 8. Output Capacitance

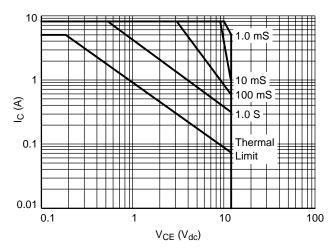
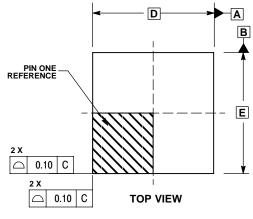


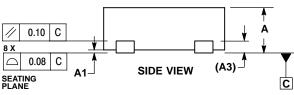
Figure 9. PNP Safe Operating Area

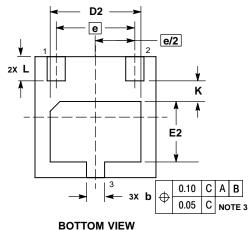
PACKAGE DIMENSIONS

WDFN3

CASE 506AU-01 **ISSUE O**



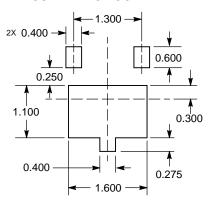




- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. CONTROLLING DIMENSION: MILLIMETERS. DIMENSION & APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN 0.25 AND 0.30 MM FROM TERMINAL.
- COPLANARITY APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS.

	MILLIMETERS				INCHES	
DIM	MIN	NOM	MAX	MIN	NOM	MAX
Α	0.70	0.75	0.80	0.028	0.030	0.031
A1	0.00		0.05	0.000		0.002
A3	0.20 REF			0.008 REF		
b	0.25	0.30	0.35	0.010	0.012	0.014
D		2.00 BSC		0.079 BSC		
D2	1.40	1.50	1.60	0.055	0.059	0.063
E	2.00 BSC			0.079 BSC		
E2	0.90	1.00	1.10	0.035	0.039	0.043
е		1.30 BSC		0.051 BSC		
K		0.35 REF		0.014 REF		
L	0.35	0.40	0.45	0.014	0.016	0.018

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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